

Notice of References Cited	Application/Control No. 10/722,484		Applicant(s)/Patent Under Reexamination YUUKI ET AL.	
	Examiner Lawrence B. Williams		Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0085656 A1	07-2002	Lee et al.	375/355
*	B	US-2003/0086339 A1	05-2003	Dally et al.	368/202
*	C	US-2004/0052152 A1	03-2004	Kono, Takashi	365/233
*	D	US-5,400,370	03-1995	Guo, Bin	375/371
*	E	US-5,451,894	09-1995	Guo, Bin	327/241
*	F	US-6,901,126 B1	05-2005	Gu, Richard	375/355
*	G	US-6,584,163	06-2003	Myers et al.	375/360
*	H	US-7,020,227	03-2006	Wang et al.	375/355
*	I	US-5,592,125	01-1997	Williams, Bertrand J.	331/1A
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Miki et al., A 50-mW/ch 2.5-Gb/s/ch Data Recovery Circuit for the SFI-5 Interface With Digital Eye-Tracking April 2004, IEEE Journal of Solid-State Circuits, Vol. 39, Issue 4, page(s) 613-621.
	V	Saito et al., A 50-mW/ch 2.5-Gb/s/ch Data Recovery Circuit for the SFI-5 Interface Using a Novel Eye-Tracking Method, 12-14 June 2003, VSLI Circuits, 2003, Digest of Digital Papers 2003 Symposium on, urnal of Solid-State Circuits, page(s) 57-60.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.